GUJARAT TECHNOLOGICAL UNIVERSITY

		GUJAKAI IECHNOLOGICAL UNIVERSIIY BE - SEMESTER-VIII EXAMINATION – SUMMER 2016			
Subject Code:182105 Date:16/05/2016					
	v	ct Name:Modern Techniques for Material Characterization (Department			
	-	e - II)			
Т	Time:10:30 AM to 01:00 PMTotal Marks: 70				
In	struct				
		 Attempt all questions. Make suitable assumptions wherever necessary. 			
		3. Figures to the right indicate full marks.			
Q.1	(a)	Explain briefly Laue method of diffraction. What are the advantages and disadvantages of Laue method?	07		
	(b)	What is Auger Electron Spectroscopy? Explain the technique with sketch of	07		
		instrumentation. Give applications and limitations.			
Q.2	(a)	Explain briefly Powder (Debye Scherrer) method of diffraction. How it is useful to study lattice parameter of crystal?	07		
	(b)	What do you mean by photoelectron spectroscopy? Explain the principle and	07		
		instrumentation of XPS. Give applications and limitations.			
	(b)	OR Explain the Nuclear Magnetic Resonance (NMR) spectroscopy. List the	07		
	(0)	applications of NMR spectroscopy.	07		
		applications of Wink spectroscopy.			
Q.3	(a)	Discuss thermogravimetric analysis technique? Explain principle involved. Mention	07		
X.C	()	the applications of Thermogravimetric analysis.	01		
	(b)	What is resolution of Microscope? Explain in detail using the formula. Write the	07		
		effect of wavelength and Numerical Aperture on resolution of microscope.			
		OR			
0.3	(a)	What do you meant by Differential scanning calorimetry? Explain principle	07		
C		involved. Give the difference between Heat flux DSC and Power Compensated			
		DSC.	~-		
	(b)	Explain Hot Stage Microscopy.	07		
0.4	(\mathbf{a})	What is TEM? Cive basis difference between SEM and TEM. With a new diagram	07		
Q.4	(a)	What is TEM? Give basic difference between SEM and TEM. With a ray diagram explain working of TEM.	07		
	(b)	Write a note on High Resolution Electron Microscopy (HREM).	07		
		OR			
Q.4	(a)	Draw schematic showing basic components of the scanning electron microscope.	07		
	(b)	Briefly explain each component and its working in SEM. What is electron microscopy? Discuss the techniques of replica preparation for	07		
	(b)	electron microscopy.	07		
05	(\mathbf{c})		07		
Q.5	(a)	With a neat sketch explain IR Spectrometer. List advantages, disadvantages and applications of IR analysis.	07		
	(b)	What is XRF? With a block diagram explain the working of XRF system.	07		

Q.5	(a)	Explain the principle and operation of FTIR spectrometer. Write advantages,	07
	(b)	disadvantages and applications of FTIR. What is Atomic Emission Spectroscopy (AES)? Explain Atomic Emission Spectroscopy. List advantages of AES.	07
